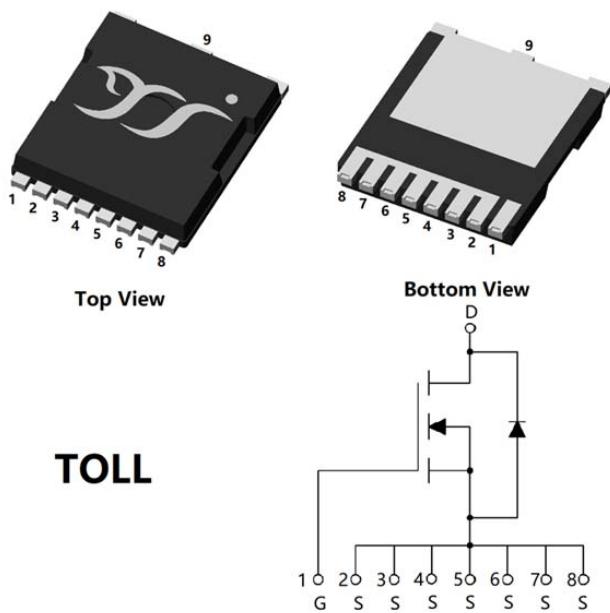




## N-Channel Enhancement Mode Field Effect Transistor



### Product Summary

- $V_{DS}$  60V
- $I_D$  250A
- $R_{DS(ON)}$  (at  $V_{GS}=10V$ )  $<2.0m\Omega$
- 100% EAS Tested
- 100%  $\nabla V_{DS}$  Tested

### General Description

- Excellent package for heat dissipation
- High density cell design for low  $R_{DS(ON)}$
- Moisture Sensitivity Level 1
- Epoxy Meets UL 94 V-0 Flammability Rating
- Halogen Free

### Applications

- Power switching application
- Uninterruptible power supply
- DC-DC convertor

### ■ Limiting Values

Parameter	Conditions		Symbol	Min	Max	Unit	
Drain-source Voltage			$V_{DS}$	-	60	V	
Gate-source Voltage			$V_{GS}$	-20	20		
Continuous Drain Current (Note 1,2)	Steady-State	$T_A=25^\circ C, V_{GS}= 10V$	$I_D$	-	27	A	
Continuous Drain Current (Note 1,3)		$T_A=100^\circ C, V_{GS}= 10V$		-	17		
Pulsed Drain Current		$T_C=25^\circ C, t_p \leq 10\mu s$		$I_{DM}$	-	1000	
Maximum Body-Diode Continuous Current		$T_C=25^\circ C$		$I_S$		185	
Avalanche energy (non-repetitive )	$T_J=25^\circ C, V_G=10V, R_G=25\Omega, L=0.5mH, IAS=48A$		EAS	-	576	mJ	
Total Power Dissipation (Note 1,2)	Steady-State	$T_A=25^\circ C$	$P_D$	-	2.9	W	
Total Power Dissipation (Note 1,3)		$T_A=100^\circ C$		-	1.16		
Junction and Storage Temperature Range	$T_J, T_{STG}$			-	240		
				-	96		

### ■ Thermal Resistance

Parameter	Symbol	Typ	Max	Units
Thermal Resistance Junction-to-Ambient (Note 2)	$R_{\theta JA}$	-	43	°C/W
Thermal Resistance Junction-to-Case	$R_{\theta JC}$	-	0.52	

### ■ Ordering Information (Example)

PREFERRED P/N	PACKING CODE	Marking	MINIMUM PACKAGE(pcs)	INNER BOX QUANTITY(pcs)	OUTER CARTON QUANTITY(pcs)	DELIVERY MODE
YJT2D0G06H	F1	YJT2D0G06H	2000	4000	20000	13" reel



## ■ Electrical Characteristics

Parameter	Symbol	Conditions	Min	Typ	Max	Units
<b>Static Parameter</b>						
Drain-Source Breakdown Voltage	$BV_{DSS}$	$V_{GS}=0V, I_D=250\mu A, Tj=25^\circ C$	60	-	-	V
		$V_{GS}=0V, I_D=10mA, Tj=25^\circ C$	60	-	-	V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS}=48V, V_{GS}=0V, Tj=25^\circ C$	-	-	1	$\mu A$
		$V_{DS}=48V, V_{GS}=0V, Tj=125^\circ C$	-	-	100	
Gate-Source Leakage Current	$I_{GSS}$	$V_{GS}=\pm 20V, V_{DS}=0V, Tj=25^\circ C$	-	-	$\pm 100$	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=250\mu A, Tj=25^\circ C$	2.2	3	3.8	V
Static Drain-Source On-Resistance	$R_{DS(on)}$	$V_{GS}=10V, I_D=50A, Tj=25^\circ C$	-	1.62	2.0	$m\Omega$
Diode Forward Voltage	$V_{SD}$	$I_S=50A, V_{GS}=0V, Tj=25^\circ C$	-	0.82	1.2	V
Gate Resistance	$R_G$	$f=1MHz, Tj=25^\circ C$	-	2.7	-	$\Omega$
<b>Dynamic Parameters</b>						
Input Capacitance	$C_{iss}$	$V_{DS}=30V, V_{GS}=0V, f=1MHz, Tj=25^\circ C$	-	4772	-	$pF$
Output Capacitance	$C_{oss}$		-	1905	-	
Reverse Transfer Capacitance	$C_{rss}$		-	210	-	
<b>Switching Parameters</b>						
Total Gate Charge	$Q_g$	$V_{GS}=10V, V_{DS}=30V, I_D=50A, Tj=25^\circ C$	-	81.1	-	$nC$
Gate-Source Charge	$Q_{gs}$		-	21.6	-	
Gate-Drain Charge	$Q_{gd}$		-	23.7	-	
Reverse Recovery Charge	$Q_{rr}$	$I_F=50A, di/dt=100A/\mu s, V_{GS}=0V, V_R=30V, Tj=25^\circ C$	-	30.7	-	$nC$
Reverse Recovery Time	$t_{rr}$		-	35.5	-	ns
Turn-on Delay Time	$t_{D(on)}$	$V_{GS}=10V, V_{DS}=30V, I_D=50A, R_{GEN}=3\Omega, Tj=25^\circ C$	-	19	-	ns
Turn-on Rise Time	$t_r$		-	58.7	-	
Turn-off Delay Time	$t_{D(off)}$		-	54.1	-	
Turn-off Fall Time	$t_f$		-	51.1	-	

### Note:

- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- The value of  $R_{\theta JA}$  is measured with the device mounted on the 40mm\*40mm\*1.1mm single layer FR-4 PCB board with 1 in<sup>2</sup> pad of 2oz. Copper, in the still air environment with  $T_A=25^\circ C$ . The maximum allowed junction temperature of 150°C. The value in any given application depends on the user's specific board design.
- Thermal resistance from junction to soldering point (on the exposed drain pad).

## ■ Typical Electrical and Thermal Characteristics Diagrams

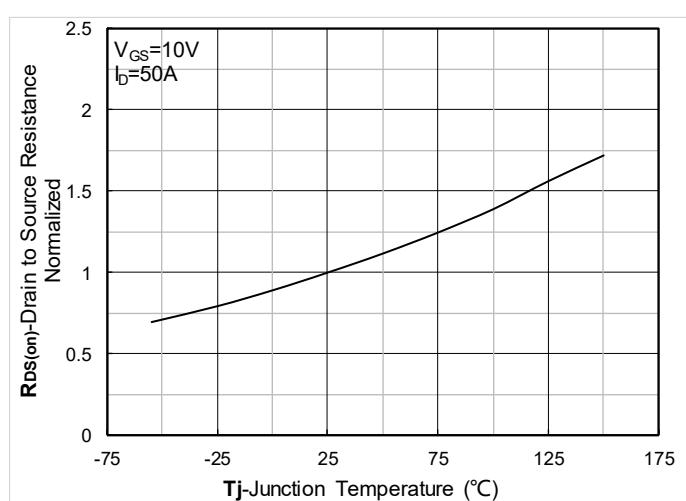
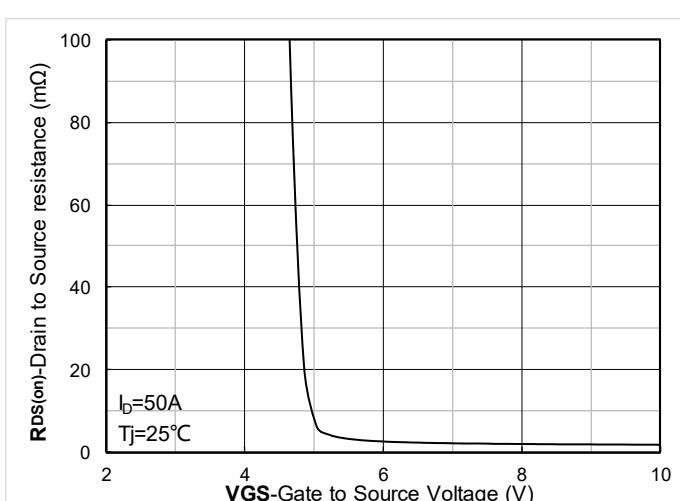
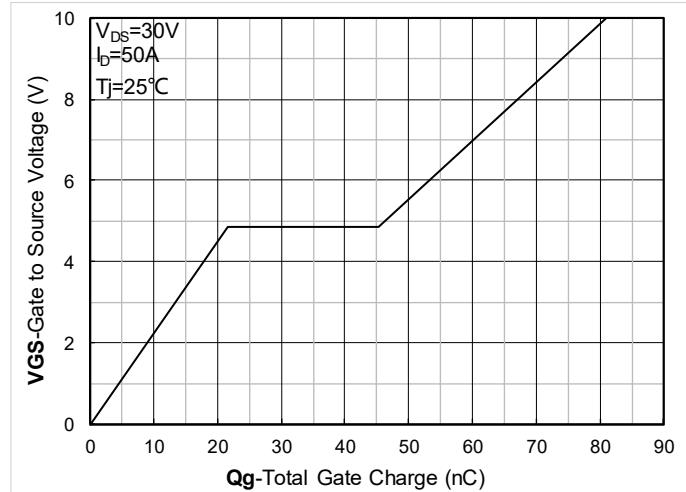
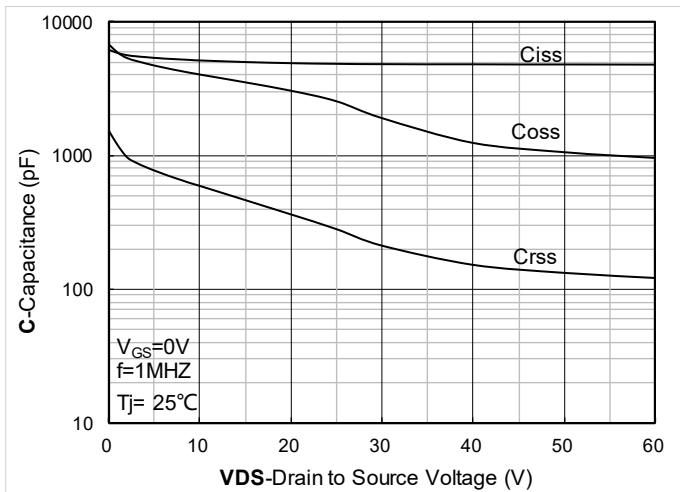
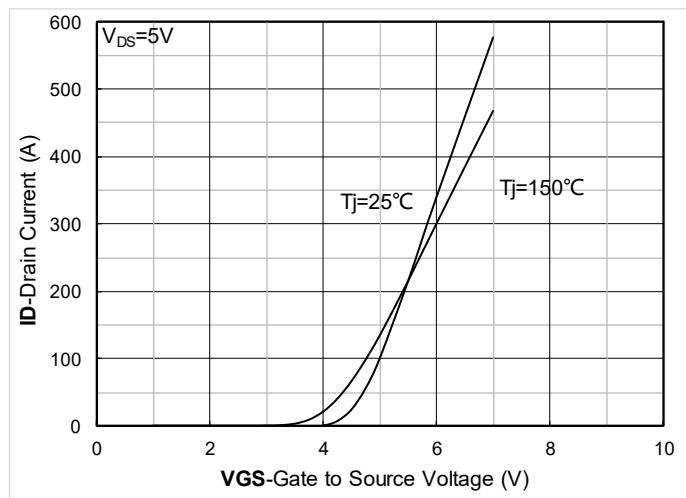
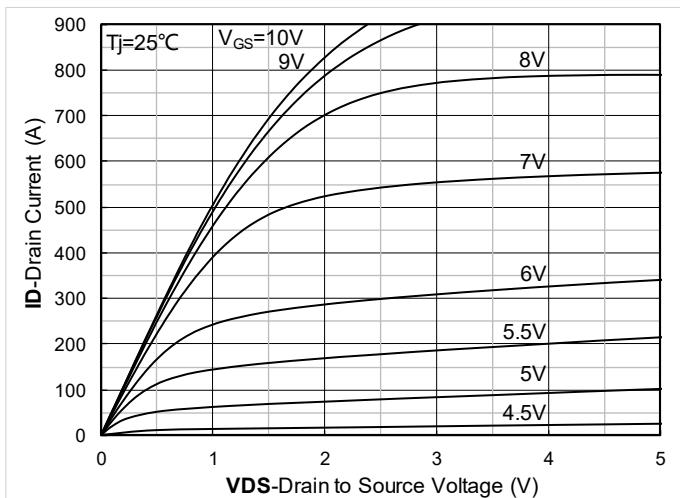
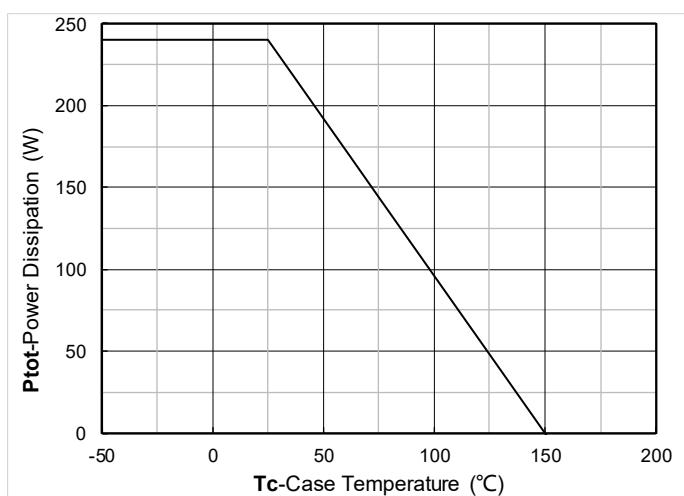
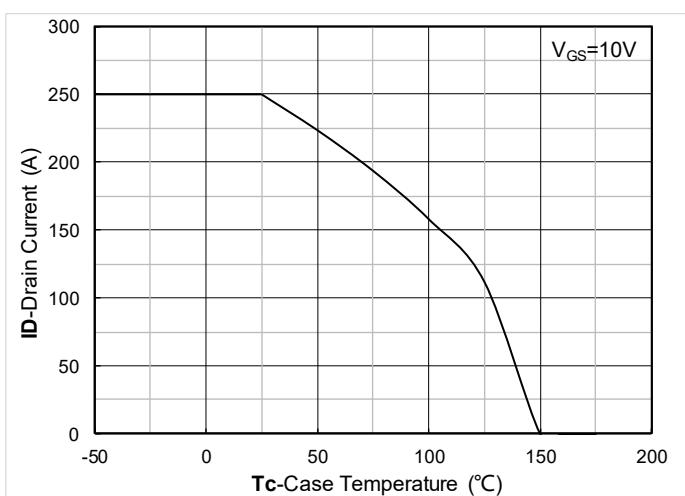
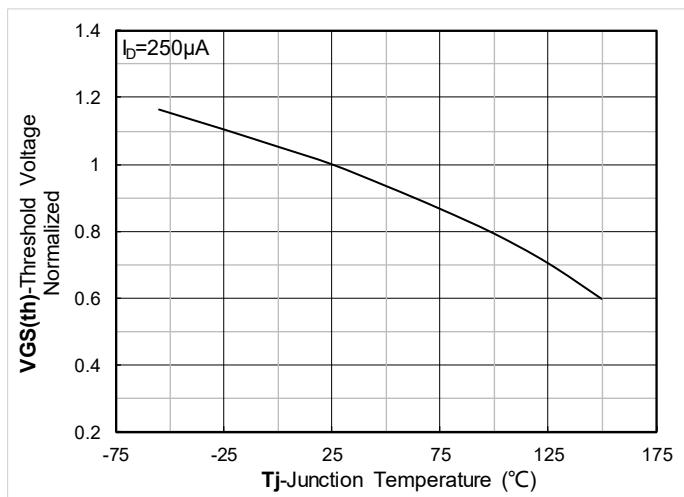
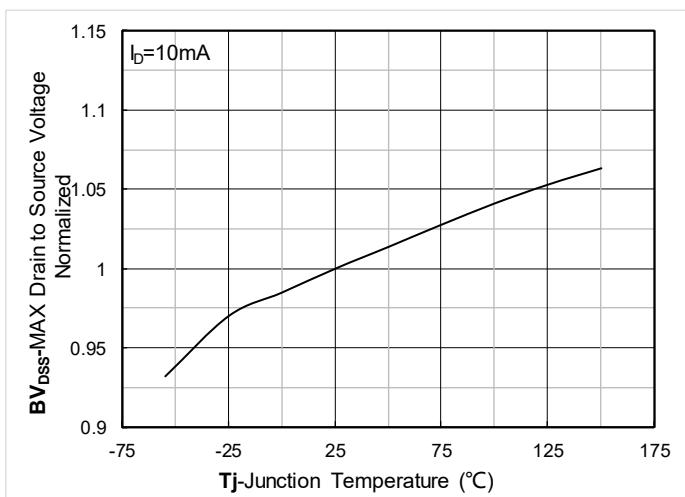
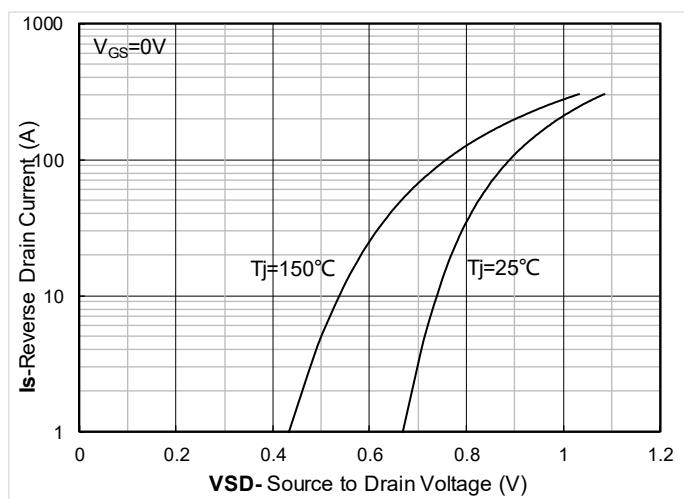
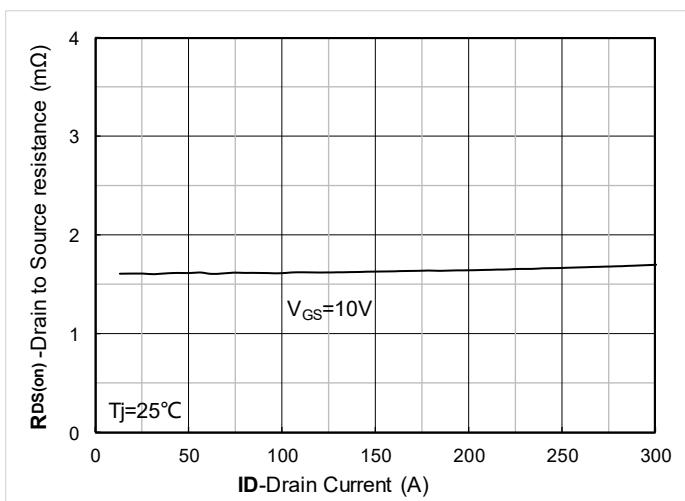


Figure 5. On-Resistance vs. Gate to Source Voltage; typical values

Figure 6. Normalized On-Resistance



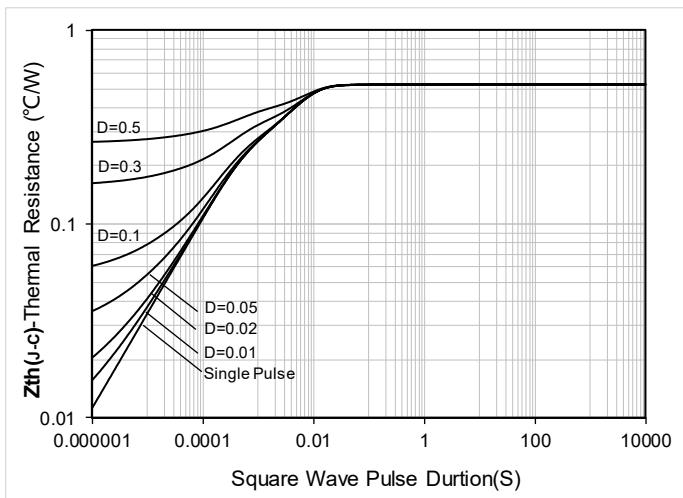


Figure 13. Maximum Transient Thermal Impedance

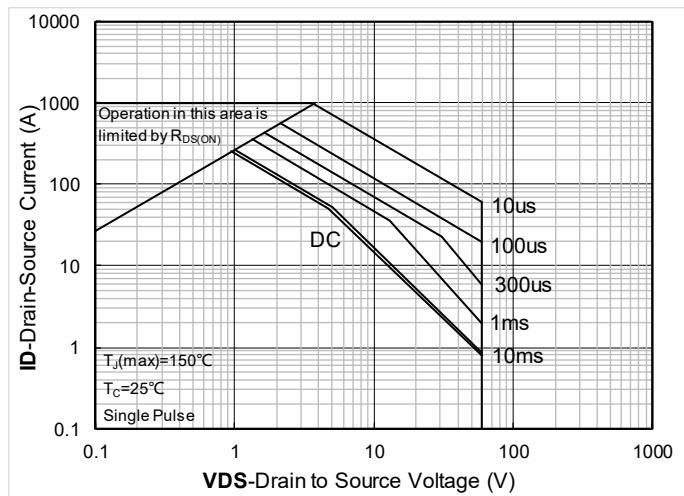


Figure 14. Safe Operation Area

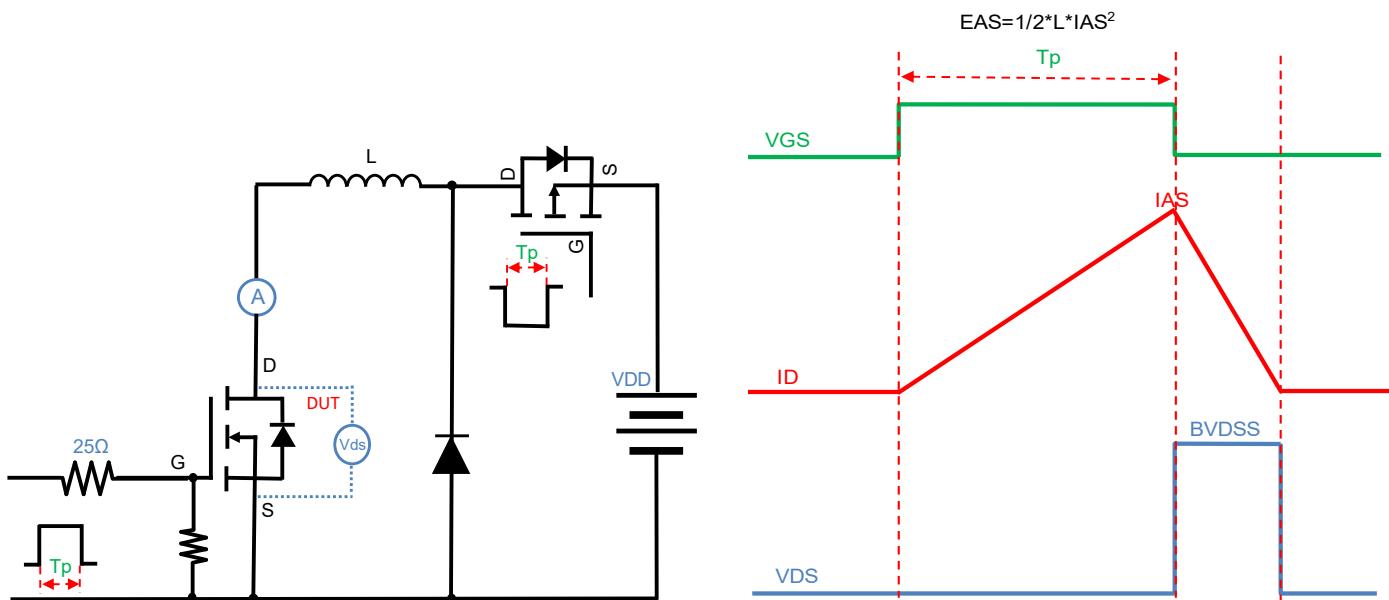
**■ Test Circuits & Waveforms**


Figure A. Unclamped Inductive Switching (UIS) Test Circuit & Waveform

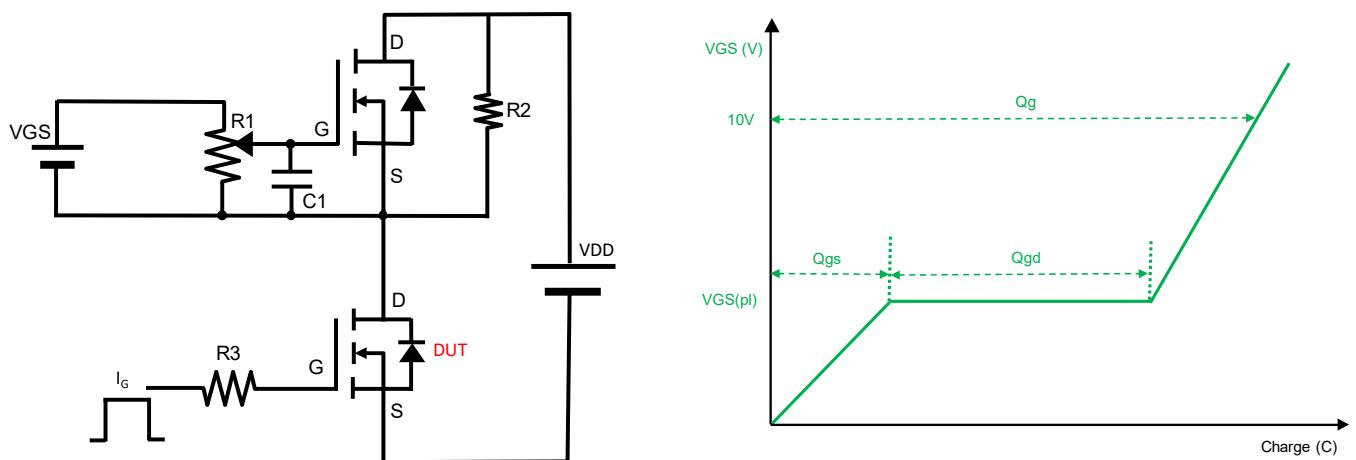


Figure B. Gate Charge Test Circuit & Waveform

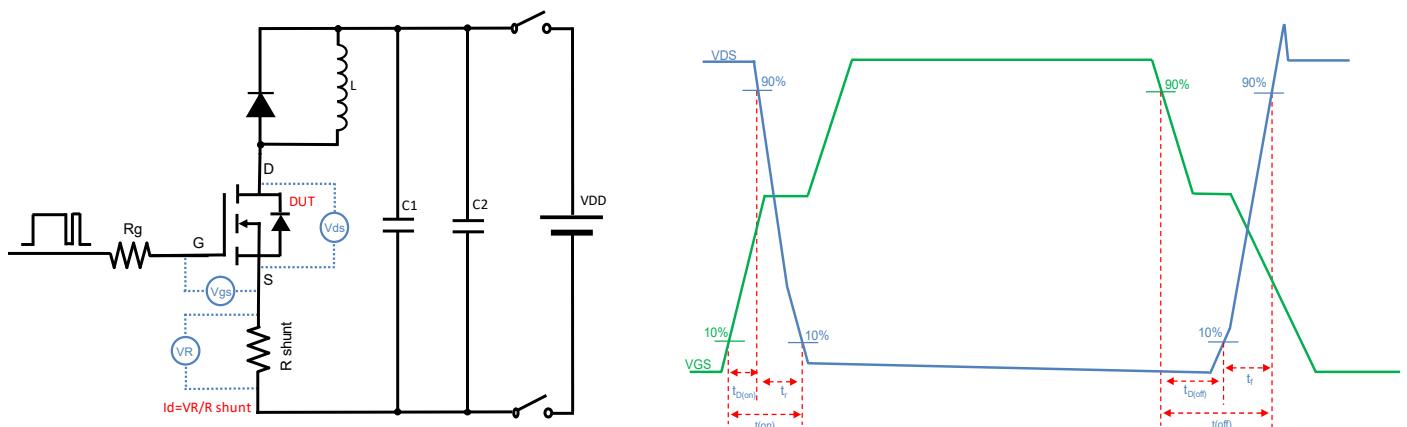


Figure C. Resistive Switching Test Circuit & Waveform

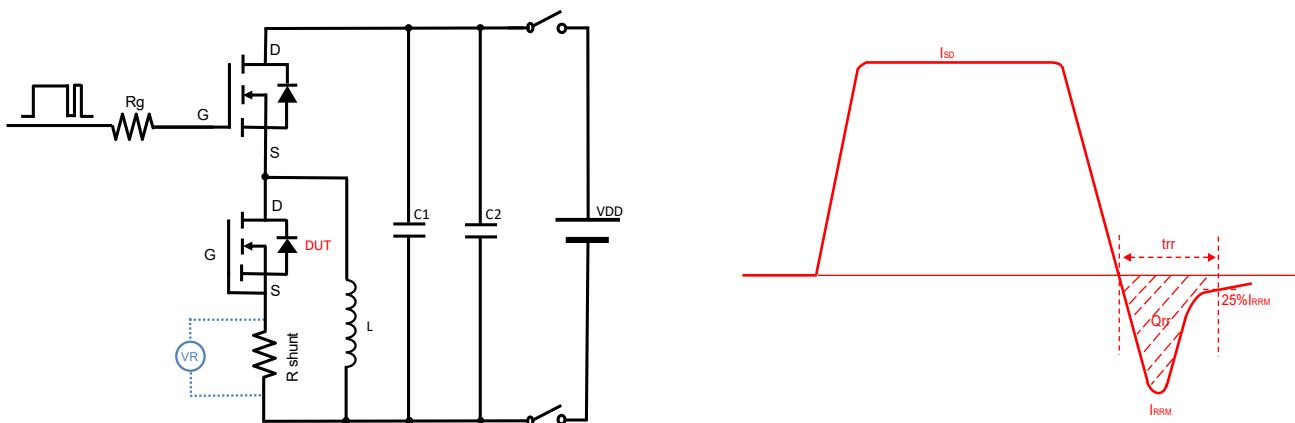
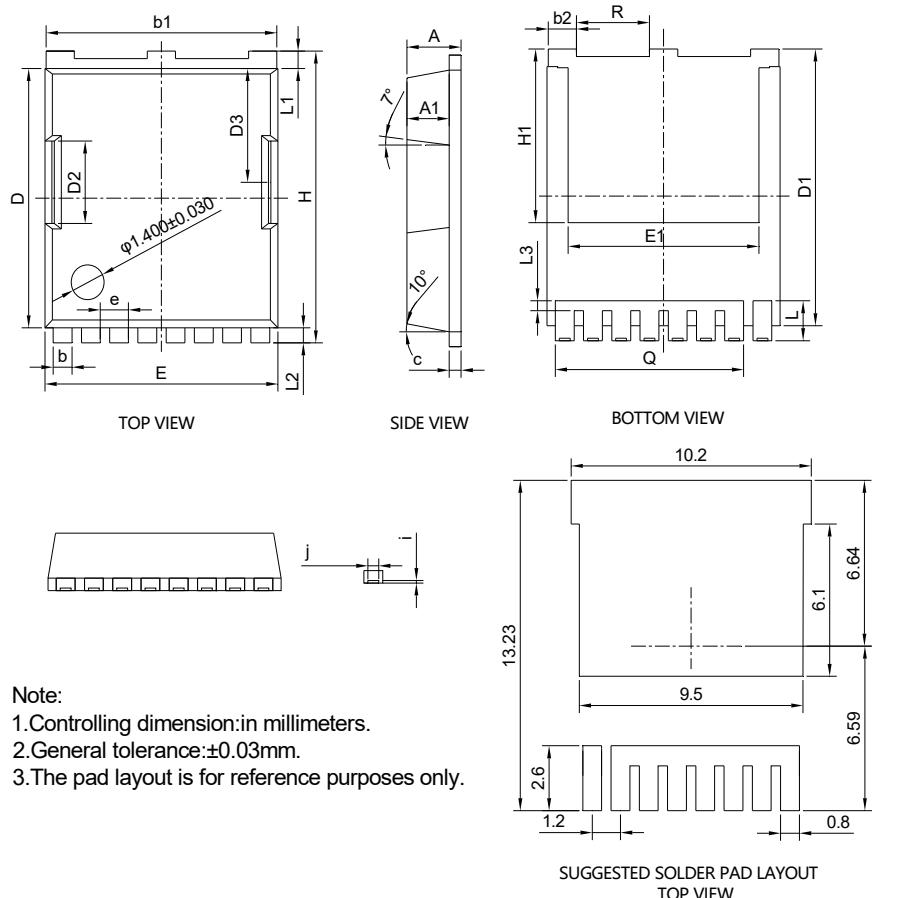


Figure D. Diode Recovery Test Circuit & Waveform

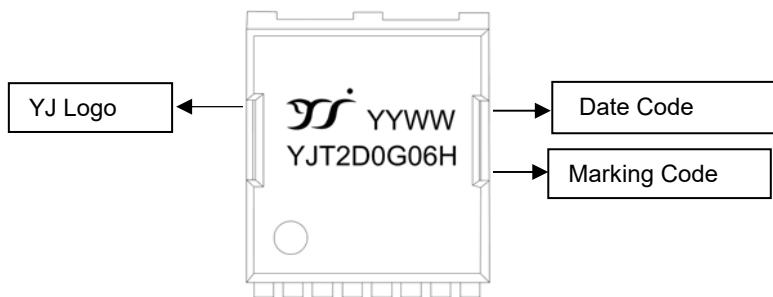


## ■ TOLL Package information





## ■ Marking Information



Note:

1. All marking is at middle of the product body
2. All marking is in laser printing
3. YJT2D0G06H is Marking Code,  
YYWW is date code, "YY" is year, "WW" is week
4. Body color: Black



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